

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251810US2		SERIAL NO. 10/828,322 New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takahiro NAKAMOTO			
				FILING DATE Herewith 04/21/2004		GROUP 2815	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>QHe</i>	AA	6,057,566	05/02/00	Kurt W. EISENBEISER, et al.	257	192	
	AB						
	AC						
	AD						
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	AI						
	AJ						
	AK						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>QHe</i>	AW	R. E. WILLIAMS, et al. "Graded Channel FET's: Improved Linearity and Noise Figure", IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. ED-25, No. 6, June 1978, pgs. 600-605					
<i>QHe</i>	AX	James A. ADAMS, et al. "Short-Channel Effects and Drain-Induced Barrier Lowering in Nanometer-Scale GaAs MESFET's", IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 40, No. 6, June 1993, pgs. 1047-1052					
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <i>Q. White</i>					Date Considered 5/18/05		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							